

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs		User Part Number PESD9V0W1BCSF Part Description											
									NXP ICN8 Protection INDI				
									BD package				
		Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects					
			TEST										
	Pre- and Post-Stress												
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below							
		MIL-STD-750-1											
	HTRB	M1038 Method A											
		Tj = Tjmax, Vr = 100% of max. datasheet											
# 5	Bias	reverse voltage	1000 hours	92	4040	0							
	тс	JESD22-A104											
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	157	6880	0							
		150000 4440											
# 0	UHAST Unbiased HAST	JESD22-A118											
# 8 or	Ulibiased HAST	Tamb = 130 °C, RH = 85 %	- 96 hours	n.a.	n.a.	n.a.							
		JESD22-A102											
,, 0	AC	Tamb = 121 °C, RH = 100 %											
# 8a	Autoclave	Pressure = 205 kPa (29.7 psia)											
		JESD22-A110											
	HAST	Tamb = 130 °C, RH = 85%, VR = 80 % of											
# 0	Highly Accelerated Stress Test	rated reverse voltage ^[1]	96 hours	156	6840	0							
# 9	rest		96 Hours	156	0840	U							
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔT_j =											
# 10	Intermittent Operating Life		1000 hours										
# 10	Intermittent Operating Life	100 C 101 13000 Cycles	1000 Hours	n.a.	n.a.	n.a.							
	RSH	JESD22-A111											
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s		n 2								
# 20	SD	200 C ± 3 C	10.5	n.a.	n.a.	n.a.							
# 21	Solderability	J-STD-002		8	240	0							
# Z1	Joiderability	J J1D 002		U	4 0	U							

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
NXP ICN8	Protection INDI	4040	0	1,1	9,51E+08

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